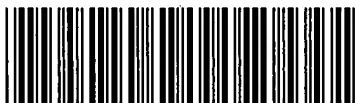


Search Notes

Application/Control No.

10/509,231

Examiner

Ibrahim A. Khan

Applicant(s)/Patent under
Reexamination

CHENG, JIANG JON

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
370	342	4/30/2007	IAK
455	452.2	4/30/2007	IAK
455	450	4/30/2007	IAK
370	252	4/30/2007	IAK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EASTImage and keyword search in USPAT, US-PGPUB, DERWENT, EPO, IBM_TDB (see attached search strategy)	4/30/2007	IAK